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		OCUMENTS			<u> </u>						
Examiner's	1	Document	Date	Name		Class	ss Sub		Filing		
nitials*		Number	MM/YY		nily Name of First Inventor)		l l	Class		Date (if appropriate)	
	AR	2002-0051885 A	1 05/200)2	Braendle et al.						
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FOREIGN	PATE	ENT DOCUMENTS					English		Translati	ion	
		Document	Date	Country	Inventor/Applicant Name		Abstract		Readily Available		
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	GR	09/095763	04/1997	JP	Mitsubishi Heavy Ind L	td	X	$oldsymbol{ol}}}}}}}}}}}}}}}}}$			
	HR	10/140330	10/140330 05/1998 JP Hitachi Tool Eng Co Ltd 08-209335 08/1996 JP Hitachi Tool Eng Ltd.		X	<u> </u>	$oxed{\bot}$				
	IR	08-209335			X	Щ.		↓_			
	JR	4-300104 10/1992 JP Mitsubishi Material Corp		X	$oldsymbol{ol}}}}}}}}}}}}}}}}}}$						
	KR	5-177413 07/1993 JP Sumitomo Electric Industries		X	$oldsymbol{ol}}}}}}}}}}}}}}}}}$						
	LR	8-209334	8-209334 08/1996 JP Hitachi Tool		X		<u> </u>				
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OTHER (II	ncludi	ng in this order Aut	hor, Title, Pe	riodical Na	me, Date, Pertinent Pages, etc.)				\perp	
		R I.C. Noyan, J. B. Cohen; "5 Determination of Strain and Stress Fields by Diffraction]	
		Methods"; Residual Stress Management by Diffraction and Interpretation; Springer-									
 ,	-	Verlag; New York; 1987;' pp. 117-130									
	RR	International Search Report December 20, 2005 in International Application No. PCT/SE2005/001311									
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not in conformance and not considered. Include copy of this form with next communication to Applicant.